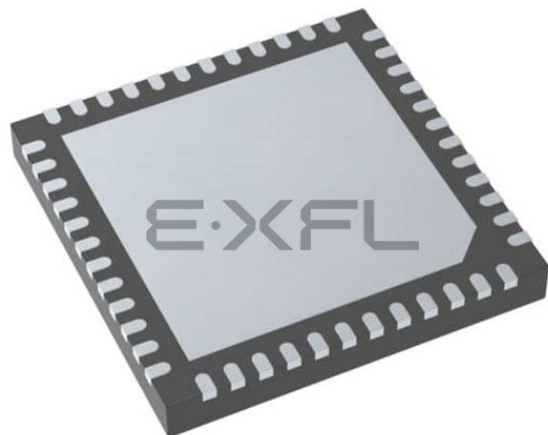




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What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	36MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	DMA, PDR, POR, PVD, PWM, Temp Sensor, WDT
Number of I/O	37
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	2V ~ 3.6V
Data Converters	A/D 10x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-UFQFN Exposed Pad
Supplier Device Package	48-UFQFPN (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f101cbu6tr

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2.3.17 SysTick timer

This timer is dedicated for OS, but could also be used as a standard down counter. It features:

- A 24-bit down counter
- Autoreload capability
- Maskable system interrupt generation when the counter reaches 0.
- Programmable clock source

2.3.18 General-purpose timers (TIMx)

There are three synchronizable general-purpose timers embedded in the STM32F101xx medium-density access line devices. These timers are based on a 16-bit auto-reload up/down counter, a 16-bit prescaler and feature 4 independent channels each for input capture, output compare, PWM or one pulse mode output. This gives up to 12 input captures / output compares / PWMs on the largest packages.

The general-purpose timers can work together via the Timer Link feature for synchronization or event chaining. Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs. They all have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

2.3.19 I²C bus

Up to two I²C bus interfaces can operate in multimaster and slave modes. They can support standard and fast modes.

They support dual slave addressing (7-bit only) and both 7/10-bit addressing in master mode. A hardware CRC generation/verification is embedded.

They can be served by DMA and they support SM Bus 2.0/PM Bus.

2.3.20 Universal synchronous/asynchronous receiver transmitter (USART)

The available USART interfaces communicate at up to 2.25 Mbit/s. They provide hardware management of the CTS and RTS signals, support IrDA SIR ENDEC, are ISO 7816 compliant and have LIN Master/Slave capability.

The USART interfaces can be served by the DMA controller.

2.3.21 Serial peripheral interface (SPI)

Up to two SPIs are able to communicate up to 18 Mbit/s in slave and master modes in full-duplex and simplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes.

Both SPIs can be served by the DMA controller.

2.3.22 GPIOs (general-purpose inputs/outputs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the

Figure 4. STM32F101xx medium-density access line LQFP64 pinout

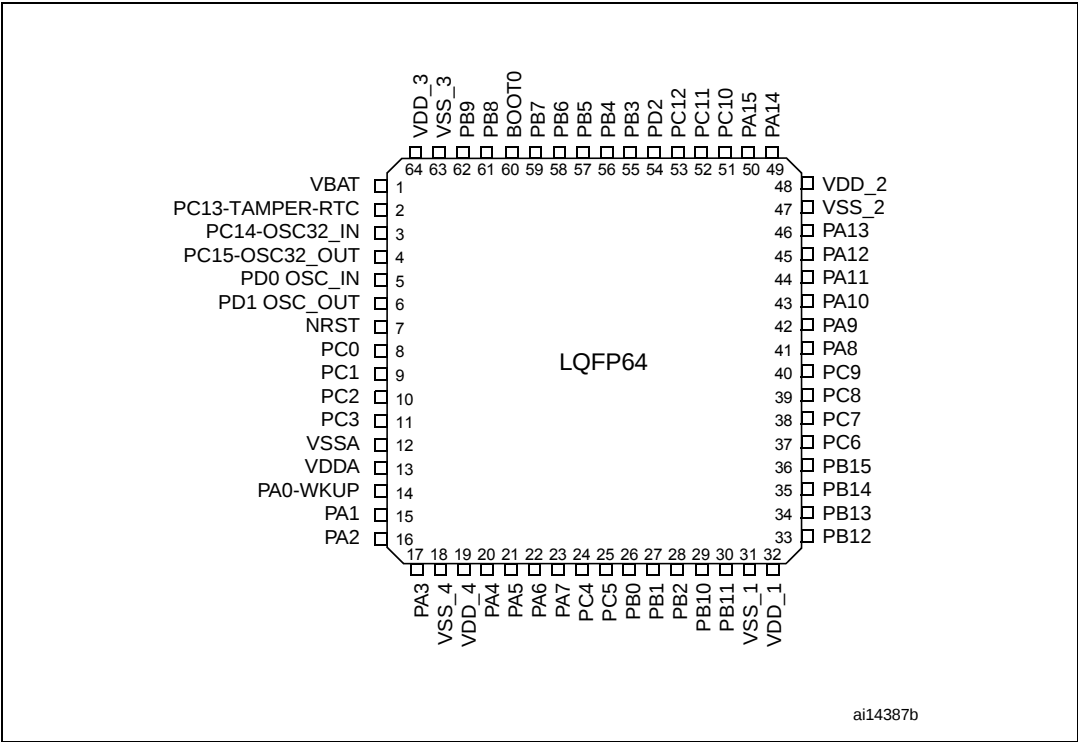


Figure 5. STM32F101xx medium-density access line LQFP48 pinout

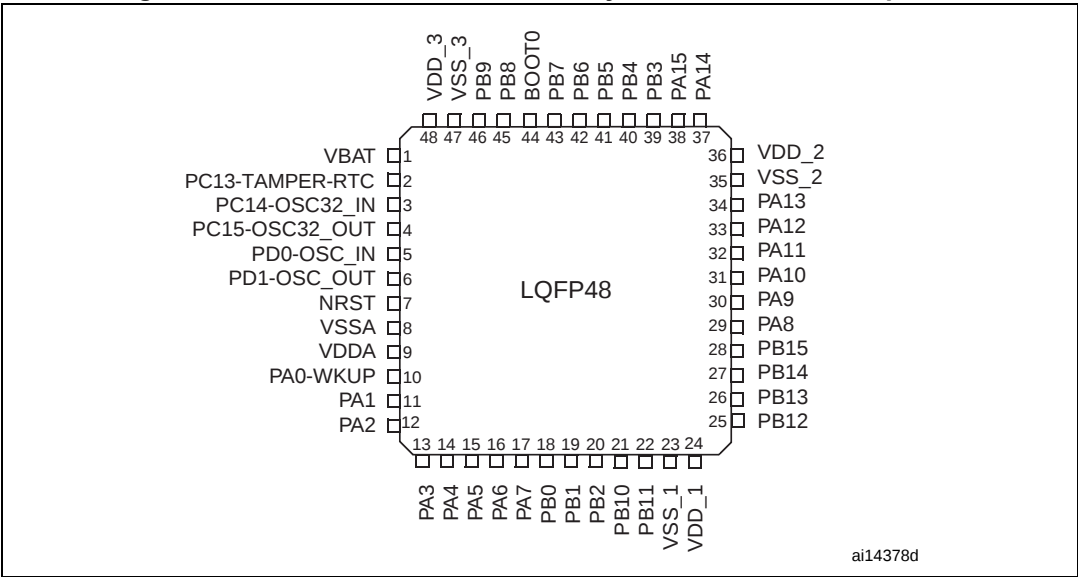


Table 4. Medium-density STM32F101xx pin definitions

Pins				Pin name	Type ⁽¹⁾	I / O level ⁽²⁾	Main function ⁽³⁾ (after reset)	Alternate functions ⁽³⁾⁽⁴⁾	
LQFP48/ UFQFPN48	LQFP64	LQFP100	VFQFPN36					Default	Remap
-	-	1	-	PE2	I/O	FT	PE2	TRACECLK	-
-	-	2	-	PE3	I/O	FT	PE3	TRACED0	-
-	-	3	-	PE4	I/O	FT	PE4	TRACED1	-
-	-	4	-	PE5	I/O	FT	PE5	TRACED2	-
-	-	5	-	PE6	I/O	FT	PE6	TRACED3	-
1	1	6	-	V _{BAT}	S	-	V _{BAT}	-	-
2	2	7	-	PC13-TAMPER- RTC ⁽⁵⁾	I/O	-	PC13 ⁽⁶⁾	TAMPER-RTC	-
3	3	8	-	PC14- OSC32_IN ⁽⁵⁾	I/O	-	PC14 ⁽⁶⁾	OSC32_IN	-
4	4	9	-	PC15- OSC32_OUT ⁽⁵⁾	I/O	-	PC15 ⁽⁶⁾	OSC32_OUT	-
-	-	10	-	V _{SS_5}	S	-	V _{SS_5}	-	-
-	-	11	-	V _{DD_5}	S	-	V _{DD_5}	-	-
5	5	12	2	OSC_IN	I	-	OSC_IN	-	PD0 ⁽⁷⁾
6	6	13	3	OSC_OUT	O	-	OSC_OUT	-	PD1 ⁽⁷⁾
7	7	14	4	NRST	I/O	-	NRST	-	-
-	8	15	-	PC0	I/O	-	PC0	ADC_IN10	-
-	9	16	-	PC1	I/O	-	PC1	ADC_IN11	-
-	10	17	-	PC2	I/O	-	PC2	ADC_IN12	-
-	11	18	-	PC3	I/O	-	PC3	ADC_IN13	-
8	12	19	5	V _{SSA}	S	-	V _{SSA}	-	-
-	-	20	-	V _{REF-}	S	-	V _{REF-}	-	-
-	-	21	-	V _{REF+}	S	-	V _{REF+}	-	-
9	13	22	6	V _{DDA}	S	-	V _{DDA}	-	-
10	14	23	7	PA0-WKUP	I/O	-	PA0	WKUP/USART2_CTS ⁽⁸⁾ / ADC_IN0/ TIM2_CH1_ETR ⁽⁸⁾	-
11	15	24	8	PA1	I/O	-	PA1	USART2_RTS ⁽⁸⁾ / ADC_IN1/TIM2_CH2 ⁽⁸⁾	-

Figure 19. High-speed external clock source AC timing diagram

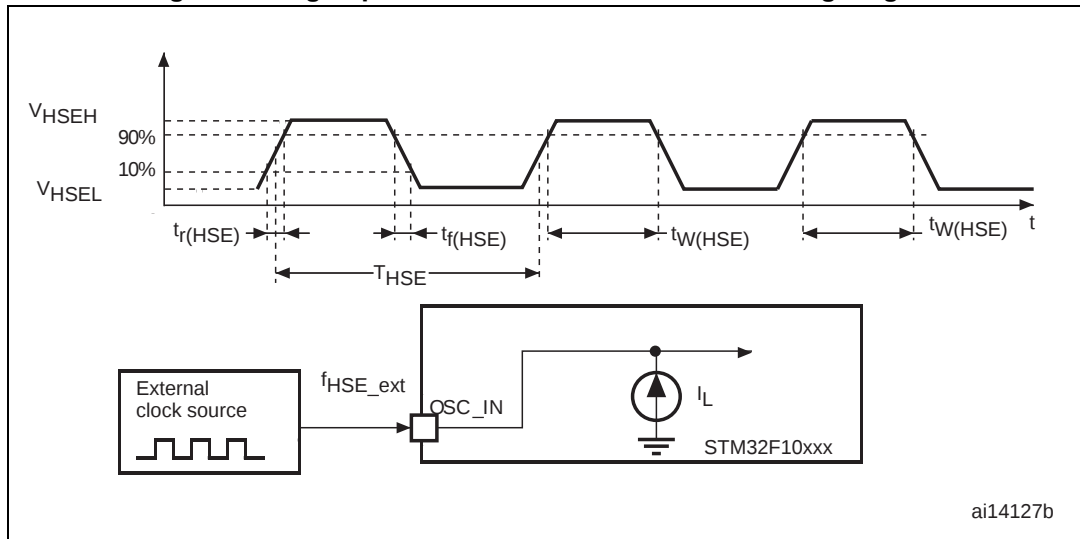
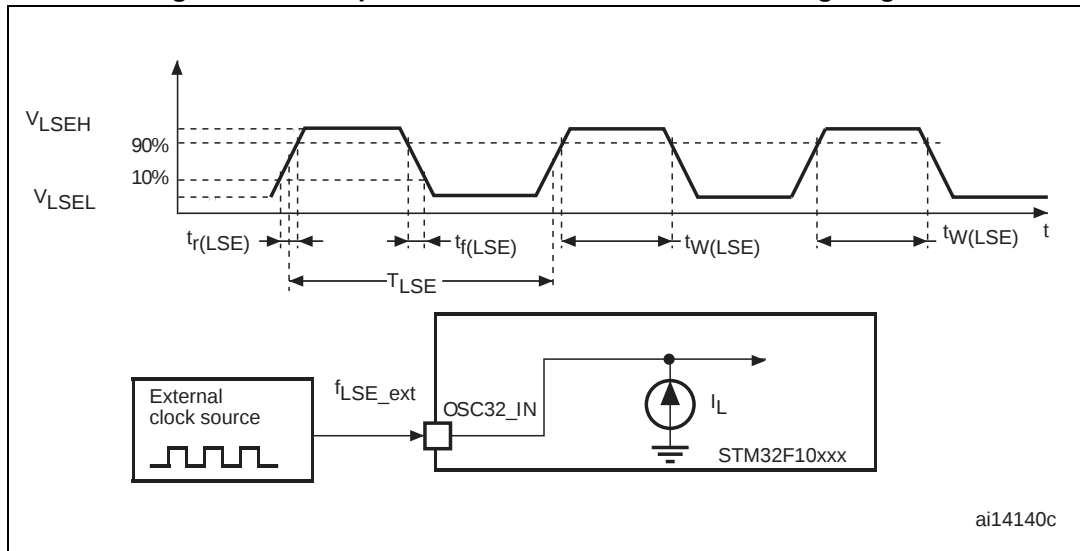


Figure 20. Low-speed external clock source AC timing diagram



High-speed external clock generated from a crystal/ceramic resonator

The high-speed external (HSE) clock can be supplied with a 4 to 16 MHz crystal/ceramic resonator oscillator. All the information given in this paragraph are based on characterization results obtained with typical external components specified in [Table 21](#). In the application, the resonator and the load capacitors have to be placed as close as possible to the oscillator pins in order to minimize output distortion and startup stabilization time. Refer to the crystal resonator manufacturer for more details on the resonator characteristics (frequency, package, accuracy).

5.3.13 I/O port characteristics

General input/output characteristics

Unless otherwise specified, the parameters given in [Table 33](#) are derived from tests performed under the conditions summarized in [Table 8](#). All I/Os are CMOS and TTL compliant.

Table 33. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IL}	Low level input voltage	Standard IO input low level voltage	-	-	$0.28 \cdot (V_{DD} - 2 \text{ V}) + 0.8 \text{ V}^{(1)}$	V
		IO FT ⁽³⁾ input low level voltage	-	-	$0.32 \cdot (V_{DD} - 2 \text{ V}) + 0.75 \text{ V}^{(1)}$	
		All I/Os except BOOT0	-	-	$0.35 V_{DD}^{(2)}$	
V_{IH}	High level input voltage	Standard IO input high level voltage	$0.41 \cdot (V_{DD} - 2 \text{ V}) + 1.3 \text{ V}^{(1)}$	-	-	V
		IO FT ⁽³⁾ input high level voltage	$0.42 \cdot (V_{DD} - 2 \text{ V}) + 1 \text{ V}^{(1)}$	-	-	
		All I/Os except BOOT0	$0.65 V_{DD}^{(2)}$	-	-	
V_{hys}	Standard IO Schmitt trigger voltage hysteresis ⁽⁴⁾	-	200	-	-	mV
	IO FT Schmitt trigger voltage hysteresis ⁽⁴⁾	-	$5\% V_{DD}^{(5)}$	-	-	
I_{lkg}	Input leakage current ⁽⁶⁾	$V_{SS} \leq V_{IN} \leq V_{DD}$ Standard I/Os	-	-	± 1	μA
		$V_{IN} = 5 \text{ V}$ I/O FT	-	-	3	
R_{PU}	Weak pull-up equivalent resistor ⁽⁷⁾	$V_{IN} = V_{SS}$	30	40	50	k Ω
R_{PD}	Weak pull-down equivalent resistor ⁽⁷⁾	$V_{IN} = V_{DD}$	30	40	50	
C_{IO}	I/O pin capacitance	-	-	5	-	pF

1. Data based on design simulation.
2. Tested in production.
3. FT = Five-volt tolerant. In order to sustain a voltage higher than $V_{DD} + 0.3$ the internal pull-up/pull-down resistors must be disabled.
4. Hysteresis voltage between Schmitt trigger switching levels. Based on characterization, not tested in production.
5. With a minimum of 100 mV.
6. Leakage could be higher than max. if negative current is injected on adjacent pins.
7. Pull-up and pull-down resistors are designed with a true resistance in series with a switchable PMOS/NMOS. This PMOS/NMOS contribution to the series resistance is minimum (~10% order).

Figure 25. 5 V tolerant I/O input characteristics - CMOS port

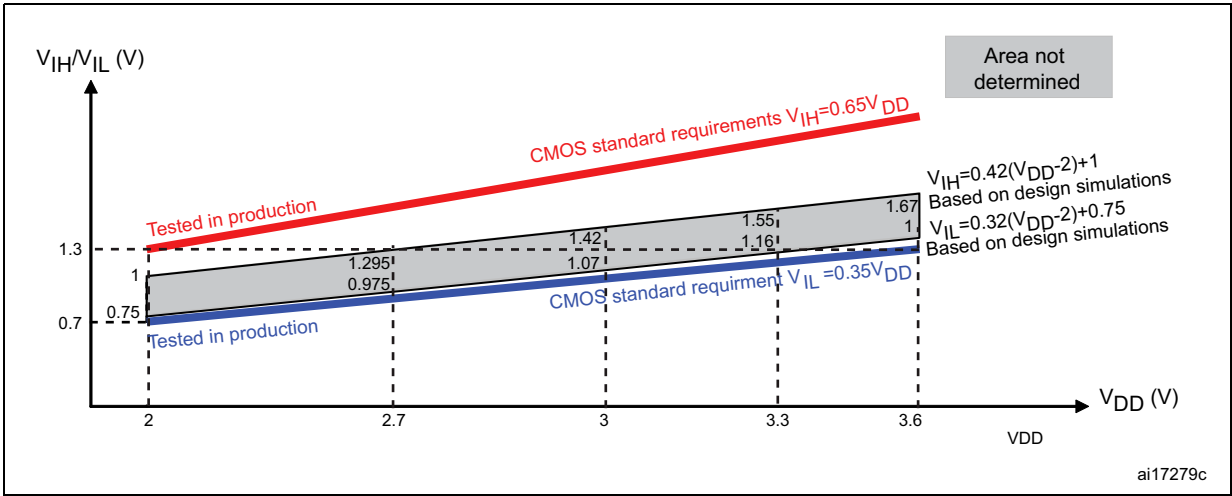
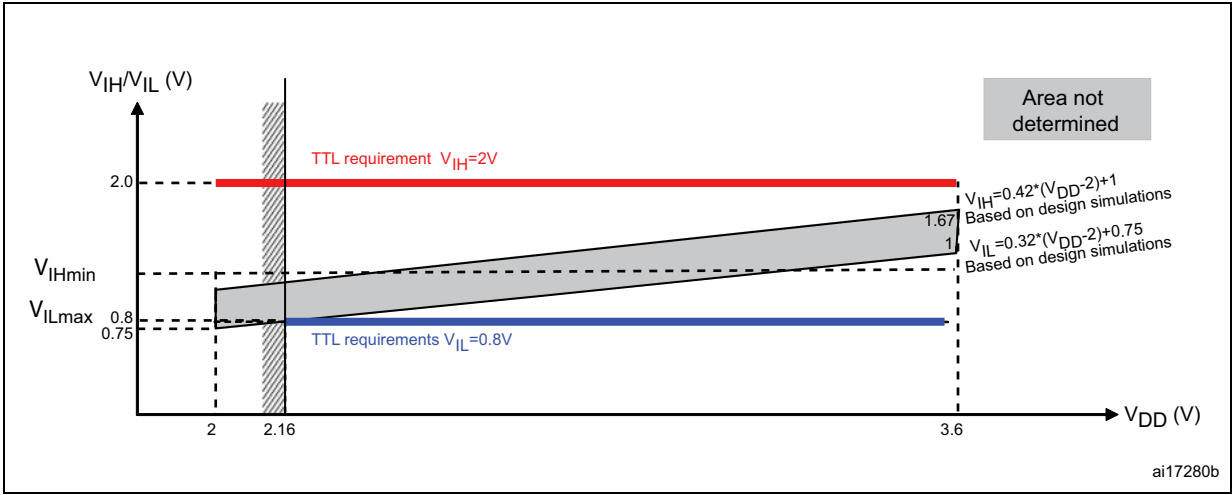


Figure 26. 5 V tolerant I/O input characteristics - TTL port



5.3.15 TIM timer characteristics

The parameters given in [Table 37](#) are guaranteed by design.

Refer to [Section 5.3.12: I/O current injection characteristics](#) for details on the input/output alternate function characteristics (output compare, input capture, external clock, PWM output).

Table 37. TIMx⁽¹⁾ characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$t_{res(TIM)}$	Timer resolution time	-	1	-	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	27.8	-	ns
f_{EXT}	Timer external clock frequency on CH1 to CH4	-	0	$f_{TIMxCLK}/2$	MHz
		$f_{TIMxCLK} = 36\text{ MHz}$	0	18	MHz
Res_{TIM}	Timer resolution	-	-	16	bit
$t_{COUNTER}$	16-bit counter clock period when internal clock is selected	-	1	65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	0.0278	1820	μs
t_{MAX_COUNT}	Maximum possible count	-	-	65536×65536	$t_{TIMxCLK}$
		$f_{TIMxCLK} = 36\text{ MHz}$	-	119.2	s

1. TIMx is used as a general term to refer to the TIM1, TIM2, TIM3 and TIM4 timers.

5.3.16 Communications interfaces

I²C interface characteristics

The STM32F101xx medium-density access line I²C interface meets the requirements of the standard I²C communication protocol with the following restrictions: the I/O pins SDA and SCL are mapped to are not “true” open-drain. When configured as open-drain, the PMOS connected between the I/O pin and V_{DD} is disabled, but is still present.

The I²C characteristics are described in [Table 38](#). Refer also to [Section 5.3.12: I/O current injection characteristics](#) for more details on the input/output alternate function characteristics (SDA and SCL).

SPI interface characteristics

Unless otherwise specified, the parameters given in [Table 40](#) are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 8](#).

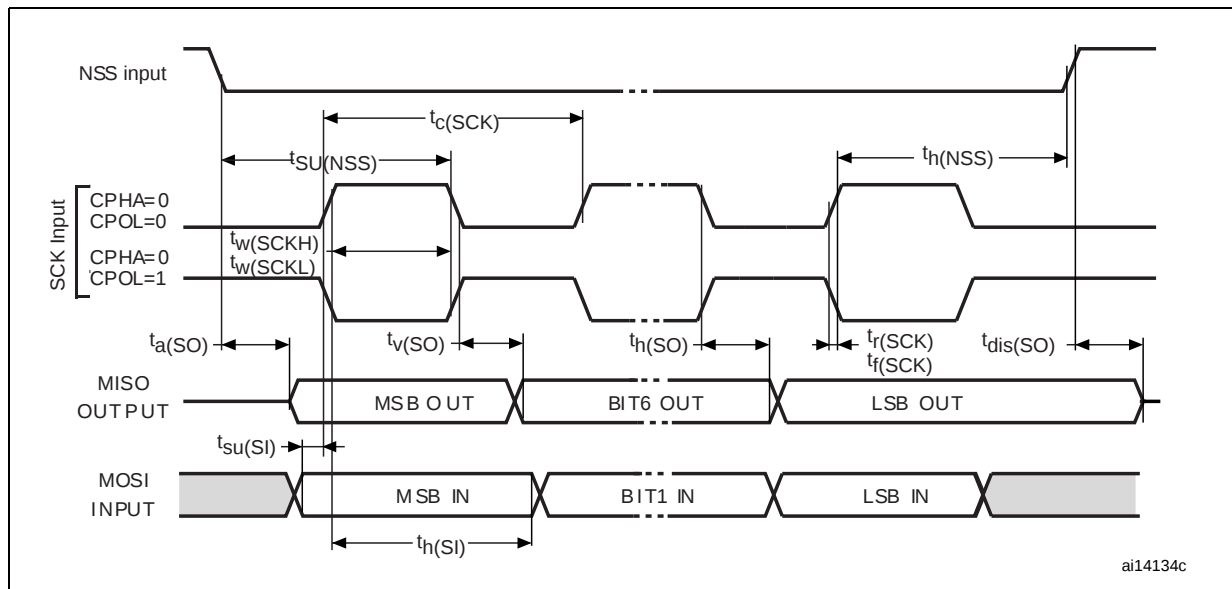
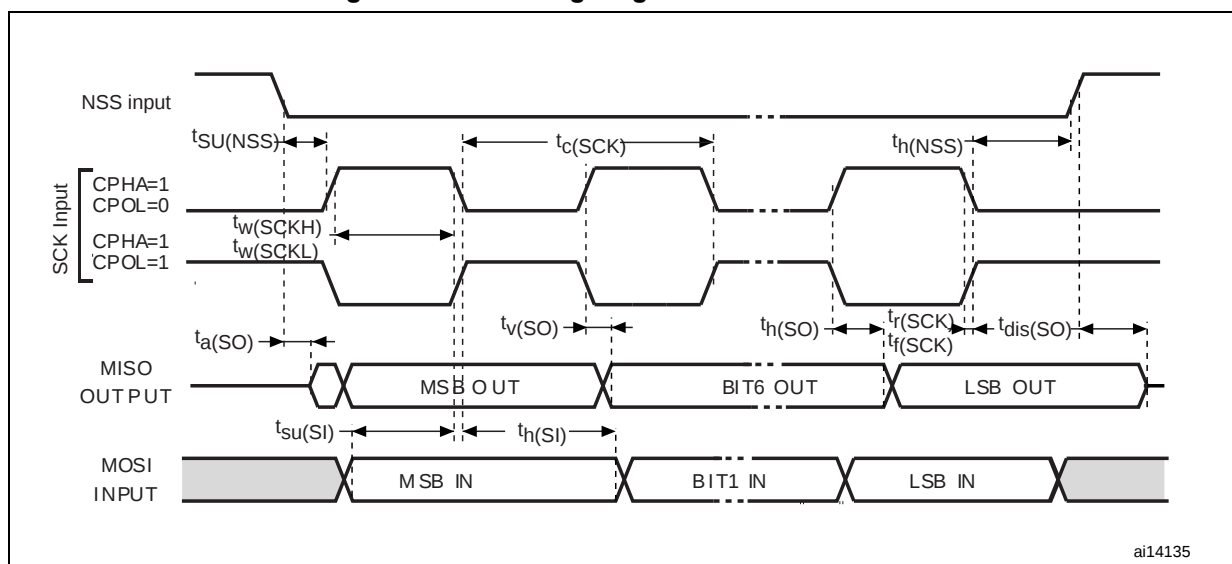
Refer to [Section 5.3.12: I/O current injection characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 40. SPI characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master mode	0	18	MHz
		Slave mode	0	18	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI clock rise and fall time	Capacitive load: C = 30 pF		8	ns
$t_{su(NSS)}^{(1)}$	NSS setup time	Slave mode	$4 t_{PCLK}$	-	
$t_{h(NSS)}^{(1)}$	NSS hold time	Slave mode	73	-	
$t_{w(SCKH)}^{(1)}$ $t_{w(SCKL)}^{(1)}$	SCK high and low time	Master mode, $f_{PCLK} = 36$ MHz, presc = 4	50	60	
$t_{su(MI)}^{(1)}$	Data input setup time Master mode	SPI1	1	-	
		SPI2	5	-	
$t_{su(SI)}^{(1)}$	Data input setup time Slave mode	-	1	-	
$t_{h(MI)}^{(1)}$	Data input hold time Master mode	SPI1	1	-	
		SPI2	5	-	
$t_{h(SI)}^{(1)}$	Data input hold time Slave mode	-	3	-	
$t_{a(SO)}^{(1)(2)}$	Data output access time	Slave mode, $f_{PCLK} = 36$ MHz, presc = 4	0	55	
		Slave mode, $f_{PCLK} = 24$ MHz	0	$4 t_{PCLK}$	
$t_{dis(SO)}^{(1)(3)}$	Data output disable time	Slave mode	10		
$t_{v(SO)}^{(1)}$	Data output valid time	Slave mode (after enable edge)	-	25	
$t_{v(MO)}^{(1)}$	Data output valid time	Master mode (after enable edge)	-	3	
$t_{h(SO)}^{(1)}$	Data output hold time	Slave mode (after enable edge)	25	-	
$t_{h(MO)}^{(1)}$		Master mode (after enable edge)	4	-	

1. Based on characterization, not tested in production.
2. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.
3. Min time is for the minimum time to invalidate the output and the max time is for the maximum time to put the data in Hi-Z

Figure 30. SPI timing diagram - slave mode and CPHA = 0

Figure 31. SPI timing diagram - slave mode and CPHA = 1⁽¹⁾

1. Measurement points are done at CMOS levels: $0.3V_{DD}$ and $0.7V_{DD}$.

Equation 1: R_{AIN} max formula:

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The formula above ([Equation 1](#)) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

Table 42. R_{AIN} max for $f_{ADC} = 14$ MHz⁽¹⁾

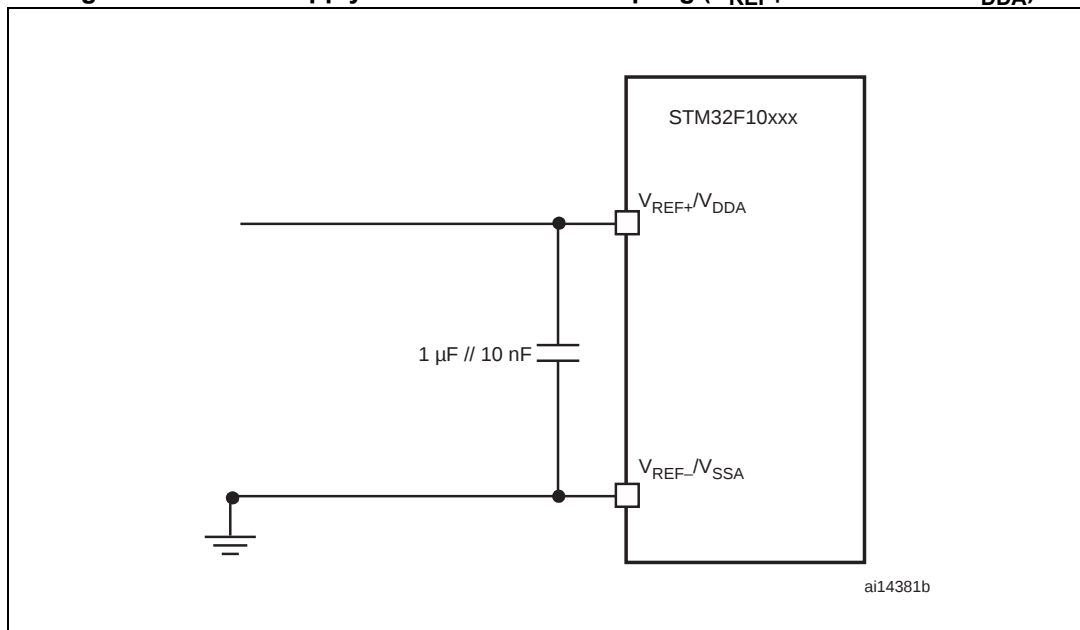
T_S (cycles)	t_S (μs)	R_{AIN} max (kΩ)
1.5	0.11	0.4
7.5	0.54	5.9
13.5	0.96	11.4
28.5	2.04	25.2
41.5	2.96	37.2
55.5	3.96	50
71.5	5.11	NA
239.5	17.1	NA

1. Guaranteed by design, not tested in production.

Table 43. ADC accuracy - limited test conditions^{(1) (2)}

Symbol	Parameter	Test conditions	Typ	Max ⁽³⁾	Unit
ET	Total unadjusted error	$f_{PCLK2} = 28$ MHz, $f_{ADC} = 14$ MHz, $R_{AIN} < 10$ kΩ, $V_{DDA} = 3$ V to 3.6 V $T_A = 25$ °C Measurements made after ADC calibration	±1.3	±2	LSB
EO	Offset error		±1	±1.5	
EG	Gain error		±0.5	±1.5	
ED	Differential linearity error		±0.7	±1	
EL	Integral linearity error		±0.8	±1.5	

- ADC DC accuracy values are measured after internal calibration.
- ADC Accuracy vs. Negative Injection Current: Injecting negative current on any analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to analog pins which may potentially inject negative current.
Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in [Section 5.3.12](#) does not affect the ADC accuracy.
- Based on characterization, not tested in production.

Figure 36. Power supply and reference decoupling (V_{REF+} connected to V_{DDA})

1. V_{REF+} and V_{REF-} inputs are available only on 100-pin packages.

5.3.18 Temperature sensor characteristics

Table 45. TS characteristics

Symbol	Parameter	Min	Typ	Max	Unit
$T_L^{(1)}$	V_{SENSE} linearity with temperature	-	± 1	± 2	$^{\circ}\text{C}$
$\text{Avg_Slope}^{(1)}$	Average slope	4.0	4.3	4.6	$\text{mV}/^{\circ}\text{C}$
$V_{25}^{(1)}$	Voltage at 25°C	1.34	1.43	1.52	V
$t_{\text{START}}^{(2)}$	Startup time	4	-	10	μs
$T_{\text{S_temp}}^{(3)(2)}$	ADC sampling time when reading the temperature	-	-	17.1	μs

1. Guaranteed by characterization, not tested in production.
2. Guaranteed by design, not tested in production.
3. Shortest sampling time can be determined in the application by multiple iterations.

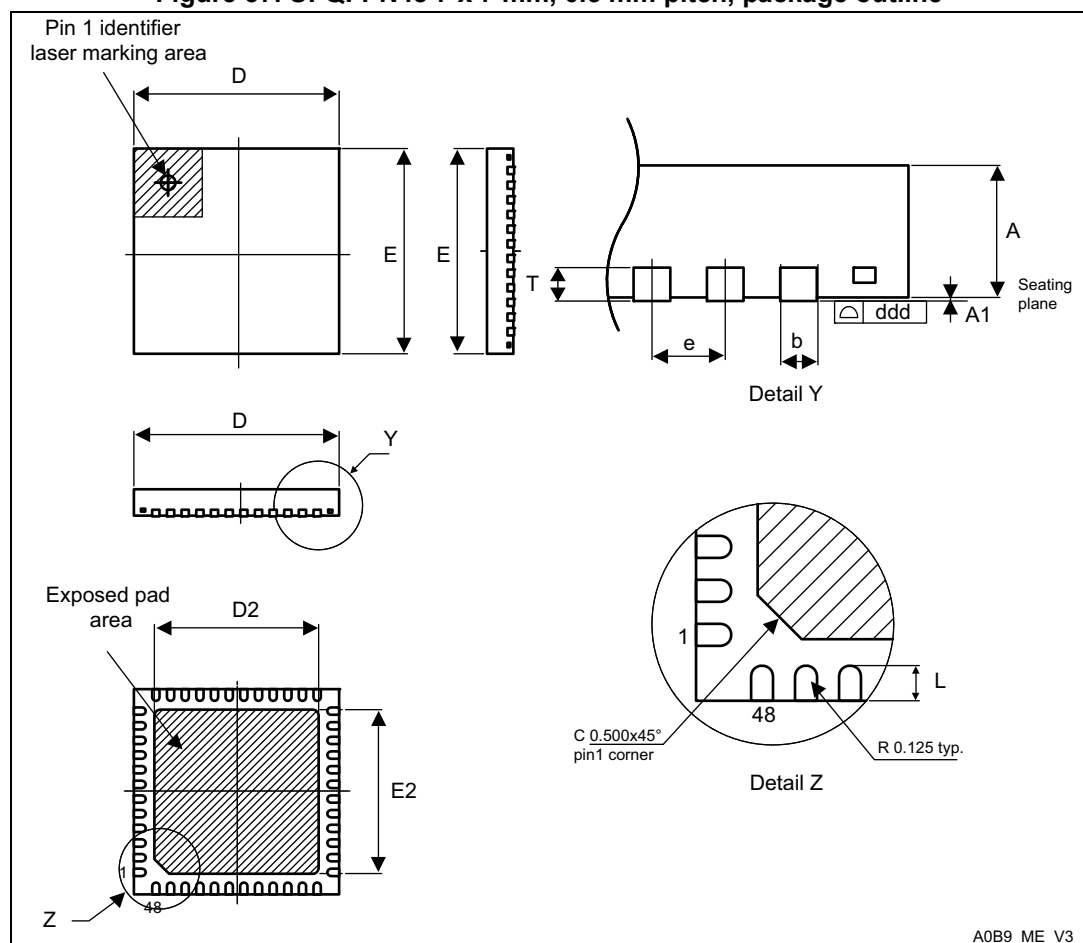
6 Package characteristics

6.1 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

6.2 UFQFPN48 package information

Figure 37. UFQFPN48 7 x 7 mm, 0.5 mm pitch, package outline

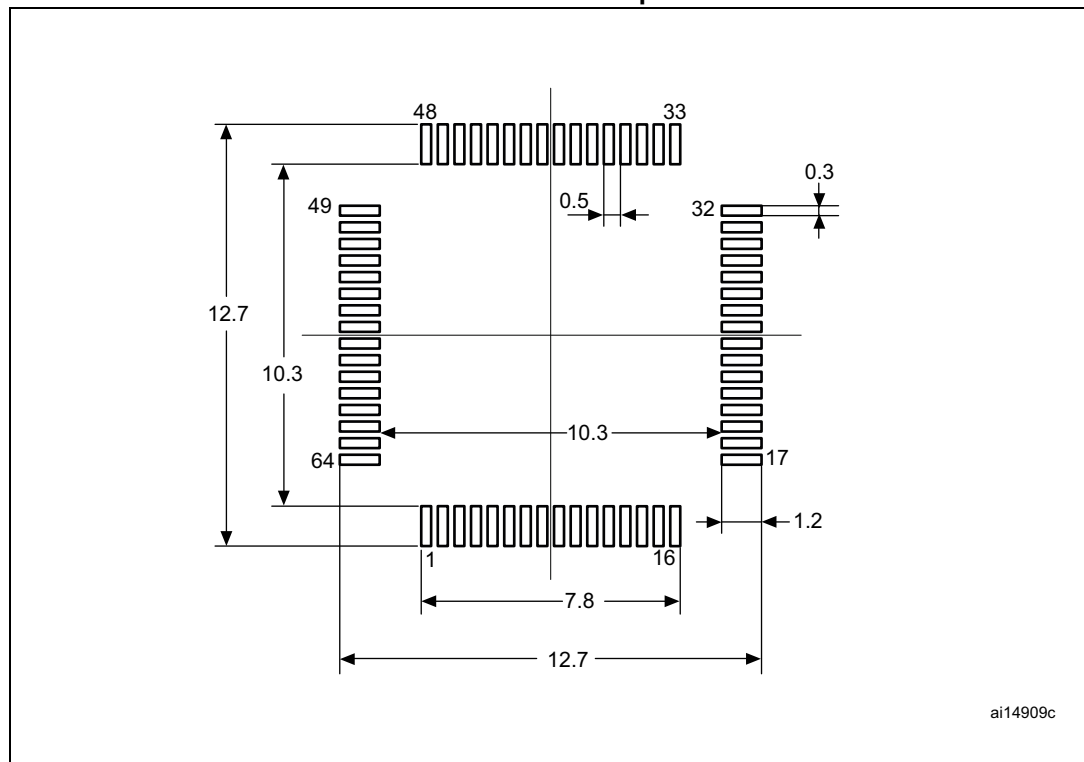


1. Drawing is not to scale.
2. There is an exposed die pad on the underside of the QFPN package, this pad is not internally connected to the VSS or VDD power pads. It is recommended to connect it to VSS.
3. All leads/pads should also be soldered to the PCB to improve the lead solder joint life.

Table 49. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data (continued)

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
E3	-	7.500	-	-	0.2953	-
e	-	0.500	-	-	0.0197	-
K	0°	3.5°	7°	0°	3.5°	7°
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
ccc	-	-	0.080	-	-	0.0031

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 47. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package recommended footprint

1. Dimensions are expressed in millimeters.

6.7 Thermal characteristics

The maximum chip junction temperature (T_{Jmax}) must never exceed the values given in [Table 8: General operating conditions on page 33](#).

The maximum chip-junction temperature, T_J max, in degrees Celsius, may be calculated using the following equation:

$$T_J \text{ max} = T_A \text{ max} + (P_D \text{ max} \times \Theta_{JA})$$

Where:

- T_A max is the maximum ambient temperature in °C,
- Θ_{JA} is the package junction-to-ambient thermal resistance, in °C/W,
- P_D max is the sum of P_{INT} max and $P_{I/O}$ max ($P_D \text{ max} = P_{INT} \text{ max} + P_{I/O} \text{ max}$),
- P_{INT} max is the product of I_{DD} and V_{DD} , expressed in Watts. This is the maximum chip internal power.

$P_{I/O}$ max represents the maximum power dissipation on output pins where:

$$P_{I/O} \text{ max} = \Sigma (V_{OL} \times I_{OL}) + \Sigma ((V_{DD} - V_{OH}) \times I_{OH}),$$

taking into account the actual V_{OL} / I_{OL} and V_{OH} / I_{OH} of the I/Os at low and high level in the application.

Table 51. Package thermal characteristics

Symbol	Parameter	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient LQFP 100 - 14 x 14 mm / 0.5 mm pitch	46	°C/W
	Thermal resistance junction-ambient LQFP 64 - 10 x 10 mm / 0.5 mm pitch	45	
	Thermal resistance junction-ambient LQFP 48 - 7 x 7 mm / 0.5 mm pitch	55	
	Thermal resistance junction-ambient UFQFPN 48 - 6 x 6 mm / 0.5 mm pitch	32	
	Thermal resistance junction-ambient VFQFPN 36 - 6 x 6 mm / 0.5 mm pitch	18	

6.7.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org.

7 Ordering information scheme

Table 52. Ordering information scheme

Example:	STM32F	101	C	8	T	6	xxx						
Device family													
STM32 = ARM-based 32-bit microcontroller													
Product type													
F = general-purpose													
Device subfamily													
101 = access line													
Pin count													
T = 36 pins													
C = 48 pins													
R = 64 pins													
V = 100 pins													
Flash memory size⁽¹⁾													
8 = 64 Kbytes of Flash memory													
B = 128 Kbytes of Flash memory													
Package													
T = LQFP													
U = VFQFPN or UFQFPN													
Temperature range													
6 = Industrial temperature range, –40 to 85 °C.													
Options													
xxx = programmed parts													
TR = tape and real													

1. Although STM32F101x6 devices are not described in this datasheet, orderable part numbers that do not show the A internal code after temperature range code 6 should be referred to this datasheet for the electrical characteristics. The low-density datasheet only covers STM32F101x6 devices that feature the A code.



For a list of available options (speed, package, etc.) or for further information on any aspect of this device, please contact the nearest ST sales office.

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